

Notice of References Cited		Application/Control No. 10/550,577	Applicant(s)/Patent Under Reexamination HAYASHI ET AL.	
		Examiner /Susan W. Berman/	Art Unit 1796	Page 1 of 1

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NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
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